

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		<b>Application No.</b>	10/678,766
		<b>Filing Date</b>	October 2, 2003
		<b>First Named Inventor</b>	Tois et al.
		<b>Art Unit</b>	1722
<i>(Multiple sheets used when necessary)</i>		<b>Examiner</b>	Matthew J. Song
SHEET 1 OF 1		<b>Attorney Docket No.</b>	SEPP21.001C1

<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initials	Cite No.	Document Number Number + Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear

<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear

<b>NON PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
	1	NIEMINEN et al., "Formation and Stability of lanthanum oxide thin films deposited from β-diketonate precursor" <i>Applied Surface Science</i> 6915: 1-12 (2001)			
	2	RITALA et al., "Zirconium dioxide thin films deposited by ALE using zirconium tetrachloride as precursor" <i>Applied Surface Science</i> 75: 333-340 (1994)			
	3	RITALA et al., "Growth of titanium dioxide thin films by atomic layer epitaxy" <i>Thin Solid Films</i> 225: 288-295 (1993)			
	4	PUTKONEN et al., "Low-Temperature ALE Deposition of Y2O3 Thin films from β-Diketonate Precursors" <i>Chemical Vapor Deposition</i> 44-50 (2001)			
	5	LESKELÄ et al., "Atomic Layer Epitaxy in Deposition of Various Oxide and Nitride Thin Films" <i>Journal De Physique IV</i> Vol. 5: 937-951 (1995)			

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Examiner Signature	Date Considered
<b>*Examiner:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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